Special Issue

Applications of Machine Learning in Image Recognition and Processing

Message from the Guest Editor

The Special Issue on “Applications of Machine Learning in Image Recognition and Processing” covers the innovative technologies or applications of rising trends in image processing and recognition. Topics of interest include, but are not limited to, the following:

- Small target detection and tracking recognition;
- Crowd counting;
- Biomedical image processing
- Intelligent agriculture;
- Intelligent aquaculture;
- Intelligent transportation;
- Intelligent surveillance;
- Forgery detection and recognition.

Guest Editor

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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